



Studies of atomic scale diffusion by x-ray photon correlation spectroscopy

M. Stana^{*1}, M. Leitner^{1,2}, M. Ross¹ and B. Sepiol¹

¹Universität Wien, Fakultät für Physik, Strudlhofgasse 4, 1090 Wien, Austria

²Technische Universität München, Forschungs-Neutronenquelle Heinz Maier-Leibnitz (FRM II), 85747 Garching, Germany

*markus.stana@univie.ac.at

1 Introduction

This poster gives an overview of the relatively new technique of **atomic scale X-ray Photon Correlation Spectroscopy (aXPCS)**, which uses the time evolution of speckle patterns in the diffuse intensity regime to

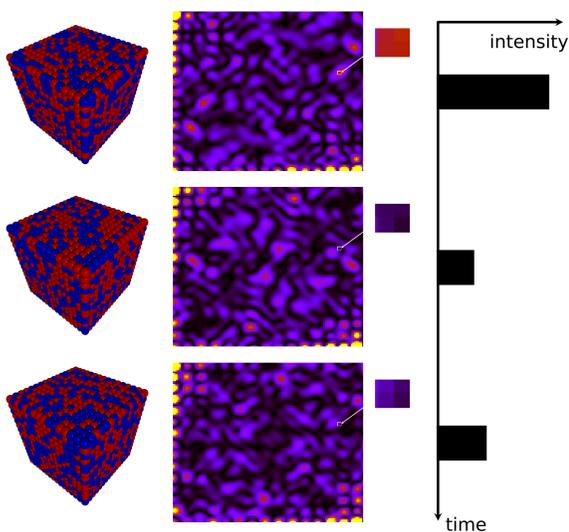
reveal diffusion mechanisms in real space. This is done via the so called **intensity autocorrelation function**.

The advantages of this new technique are its **sensi-**

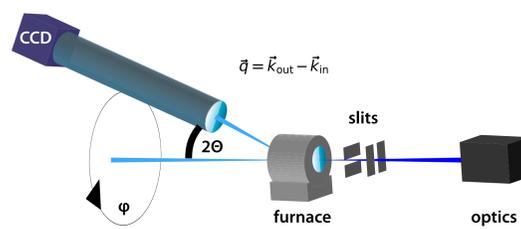
tivity to jump mechanisms, its applicability at very low temperatures, i.e. for **very low diffusion rates** and for a broad variety of systems (**not element specific**).

2 Experiment and theoretical background

Different real space configurations yield different intensities in the diffuse regime (here in (100) plane):

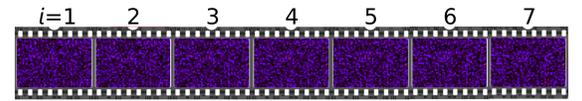


In the experiment a CCD camera collects a series of images from a detail of reciprocal space corresponding to a certain \vec{q} and for a certain T :



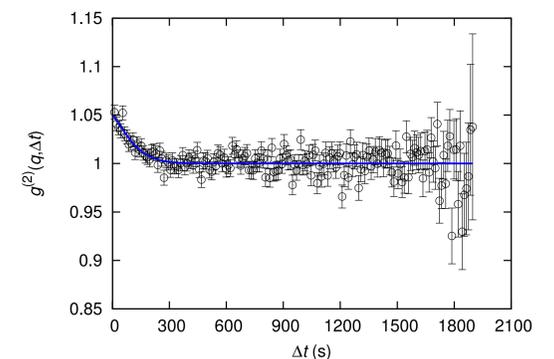
Variable parameters in the experiment:

- scattering vector \vec{q}
 - scattering angle 2θ
 - azimuthal angle φ
 - $|\vec{k}_{in}| = |\vec{k}_{out}| \propto E_{beam}$
- temperature T
- sample orientation relative to \hat{k}_{in}
- exposure time \rightarrow frame rate



CCD images for different t at particular \vec{q} are used to calculate the Intensity Autocorrelation function:

$$g^{(2)}(\vec{q}, \Delta t) = \frac{\langle I(\vec{q}, t)I(\vec{q}, t + \Delta t) \rangle}{\langle I(\vec{q}, t) \rangle^2} = 1 + \beta \exp\left(-2\frac{\Delta t}{\tau(\vec{q})}\right) \quad (1)$$



3 Finding a diffusion model

General form of correlation time $\tau(\vec{q})$:

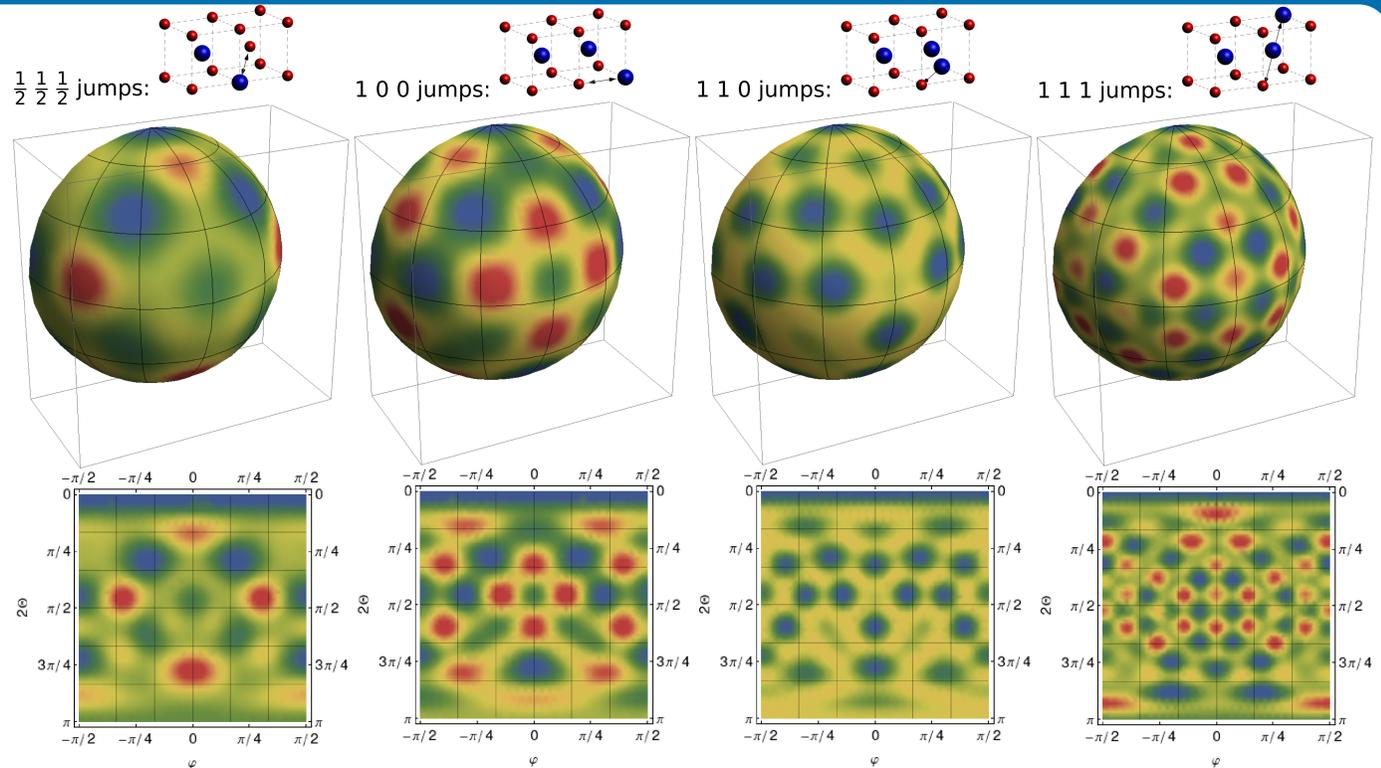
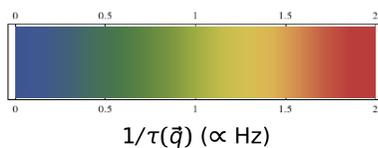
$$\tau(\vec{q}) = \tau_0 \frac{I_{SRO}(\vec{q})}{\sum_n P_n \sum_{\Delta \vec{a}_{nj}} (1 - \exp(i\vec{q} \cdot \Delta \vec{a}_{nj}))} \quad (2)$$

This can be calculated for a particular system and certain parameters:

- short-range order intensity I_{SRO}
- neighbors for certain lattice type $\Delta \vec{a}_n$
- lattice constant d
- crystal orientation

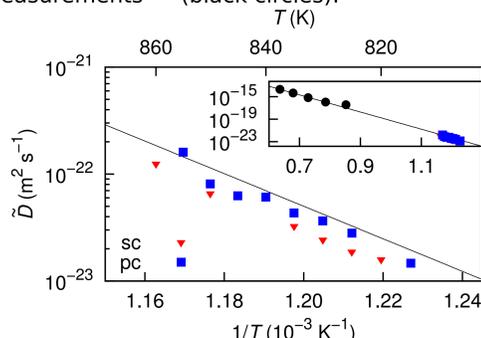
Notice: the sample to detector distance is only a scaling factor.

An example of inverse correlation times $1/\tau(\vec{q})$ in a bcc system oriented with $\hat{k}_{in} \parallel (110)$ and with $I_{SRO} = 1$ for different jump vectors is given to the right:

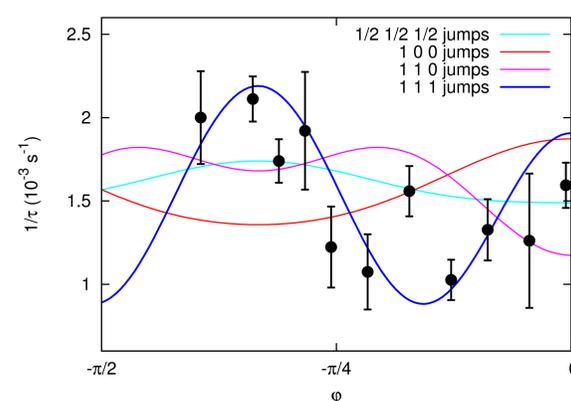


4 Some results

$\text{Ni}_{97}\text{Pt}_3$ solid solution^[1] single crystalline (sc) and polycrystalline (pc) sample measured at different temperatures compared with tracer measurements^[2] (black circles):



$\text{Fe}_{55}\text{Al}_{45}$ binary intermetallic alloy^[3] compared with diffusion models with $I_{SRO}(\vec{q}) = 1$:



In the first example of $\text{Ni}_{97}\text{Pt}_3$ one can see that **aXPCS measurements agree well with tracer measurements**. The advantage of aXPCS measurements here is the possibility to measure at very low diffusion rates corresponding to very low temperatures. The other big advantage, as can be seen in the example of $\text{Fe}_{55}\text{Al}_{45}$, is the possibility to identify diffusion mechanisms. In this case, even though the inclusion of $I_{SRO}(\vec{q}) \neq 1$ could still change this picture, the **111 jump mechanism seems dominant**.

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^[2] M. S. A. Karunaratne and R. C. Reed, Acta mater., 51(10) (2003) 2905-2919.

^[3] Data measured at PETRA III at $E = 7$ keV, $2\theta = 20^\circ$ and $T = 653$ K (preliminary results).